

Flexible, Productive, Robust,

Specifications



Introduction

Agilent 720/730 Series ICP-0ES spectrometers are manufactured according to a quality management system certified to ISO 9001.

Design overview

The Agilent 720/730 Series are compact, bench-mounted simultaneous Inductively Coupled Plasma Optical Emission Spectrometers (ICP-OES) with full PC control of all instrument settings and compatible accessories. They feature a custom-designed CCD detector with unique image mapping (I-MAP) technology, providing complete wavelength coverage from 167–785 nm.

Agilent ICP-0ES systems are available in either radially (725/735) or axially (720/730) viewed configuration with a choice of sample introduction system to suit your application needs. These instruments include a free-running, air-cooled 40 MHz RF generator with solid-state HV power supply, purged echelle polychromator and full PC control of plasma viewing positioning and plasma gas flows. Fully web-integrated ICP Expert II software uses Agilent's worksheet concept for ease of use, rapid operator training, and commonality with other Agilent spectroscopy products. The Agilent 730/735 systems feature a computer-controlled, fast rinse Switching Valve System (SVS 1) providing immediate washout of the sample introduction system for greater productivity and reduced running costs.



Instrument hardware

Sample introduction

Includes standard one-piece quartz torch optimized for high precision and sensitivity at low gas flows and low power. Choice of sample introduction system when ordering spectrometer. Choices include:

- Inert double-pass cyclone spraychamber and V-groove nebulizer (radial only)
- Glass, double-pass cyclone spraychamber and SeaSpray nebulizer (radial or axial)
- Glass, single-pass cyclone spraychamber and SeaSpray nebulizer (axial only)
- Glass single-pass cyclone spraychamber and Conikal nebulizer (axial only)
- Fully PC-controlled peristaltic pump, variable speed from 0–50 rpm, three or four channel option for sample, drain, internal standard/ ionization buffer and SVS fast rinse solution
- Optional semi and fully-demountable torches with choice of quartz or ceramic injector tubes, high solids torch and all-glass sample introduction system

Gas control

Plasma and auxiliary gas flows are software controlled using switched flow controllers. The system is fully interlocked against gas failure.

- Nebulizer gas: software enabled with choice of flow control using a high precision pressure regulator, or computer controlled using Mass Flow Controller (MFC standard on 730/735). 0–1.3 L/min in 0.01 L/min increments (with MFC)
- Plasma gas 0–22.5 L/min in 1.5 L/min increments
- Auxiliary gas 0-2.25 L/min in 0.75 L/min increments

RF generator

- 40 MHz free-running, air-cooled RF generator. Power output of 700–1500 W in 50 W increments. Optimum power settings defined and stored within each method for different sample types
- · Over 75% RF coupling efficiency
- Automatic ignition and shutdown with user-customizable ignition sequence
- Power output stability is better than 0.1%

Plasma configuration

Radially viewed system (725/735 ICP-0ES)

Vertically oriented, radially viewed plasma is ideal for the most difficult of applications, including the analysis of oils and organic solvents, geological/metal digests and high TDS solutions e.g., brines. Includes full PC control of plasma viewing height from 0–20 mm and horizontal adjustment of ±3 mm to optimize sensitivity and minimize interferences. Viewing height may be adjusted under PC control for each emission line of interest.

Axially Viewed System (720/730 ICP-0ES)

Horizontally oriented, axially viewed plasma is ideal for high sensitivity analyses. Provides a 3–12 fold improvement in detection limits compared to radial viewing. The axially viewed plasma system features a unique Cooled Cone Interface (CCI) to prevent the cooler plasma tail from being viewed by the optics. This reduces interferences, improves the system's tolerance to high dissolved solids and extends the linear dynamic range compared to conventional axial systems. The CCI is a superior plasma interface with lower running costs compared to shear gas systems. Includes full X, Y adjustment of plasma viewing position under PC control.

Instrument hardware

Optical system

- Computer-optimized echelle optical design with no moving optical parts ensures lowest detection limits and maximum stability
- 400 mm focal length polychromator is thermostatted to 35 °C for excellent stability. Features a CaF₂ prism cross disperser and echelle grating (94.74 lines/mm) creating an echellogram of 70 orders projected onto the custom-designed CCD detector
- Standard polychromator purge of 0.75 L/min with PC controlled 3 L/min boost purge for operation with emission lines having wavelengths below 185 nm. Can be purged with either argon or nitrogen (720/725 requires optional nitrogen purge kit)

CCD detector

- Custom-designed CCD detector features Image Mapping Technology (I-MAP) providing full wavelength coverage from 167-785 nm. The detector is mounted on a triple-stage Peltier device and cooled to -35 °C for low dark current and noise
- Adaptive Integration Technology (AIT) allows intense and trace signals to be measured simultaneously at the optimum signal to noise ratio. AIT automatically allocates a pixel read time to each of the selected wavelengths – more intense peaks are allocated shorter integration times and less intense peaks are allocated longer times. Unlike conventional simultaneous systems which sequence these read steps, Adaptive Integration Technology can conduct these readings at the same time providing true simultaneous measurement
- Custom-designed detector features the fastest available read-out speed of any spectroscopic CCD detector – with a 1 MHz clocking speed to process pixels. Total read-out time for a full illumination of all pixels on the detector is approximately 0.8 seconds. Duplex read-out circuitry is provided on both sides of the detector, halving read-out processing time
- CCD detector features anti-blooming protection on each individual pixel, enabling the simultaneous measurement of trace level analytes in the presence of nearby intense signals

Instrument software

Features

ICP Expert II is an easy-to-use, web-integrated instrument software package. It features wizards that guide users through method and sequence development and method templates for rapid development of commonly used methods.

- Computer control of plasma gas flows, plasma viewing position, ignition, RF power, safety interlocks and utilities monitoring
- Choice of background correction techniques from traditional off-peak background correction to unique fitted background correction
- Fast Automated Curve-fitting Technique (FACT) for online spectral deconvolution of complex spectra
- AutoMax auto-optimization of key instrument parameters
- SmartRinse optimizes the rinse time between samples, improving productivity
- MultiCal assists in extending linear dynamic range and automatic validation of results
- Time Resolved Signal (TRS) capability for interfacing to chromatographic (such as HPLC) and other separation techniques
- Calibration routines for multi-element external calibration and method of standard addition

Instrument software

Features

- Calibration reslopes eliminate the need for full re-calibration
- User-customizable Quality Control Protocols (QCP) designed to meet US EPA and other international compliance standards
- Fully editable sample label list with optional customer and batch label fields
- Weight/volume/dilution correction factors with user-definable concentration units conversion for samples and calibration/QC solutions
- Autosampler rack and tube positions can be edited for true random access sampling
- Calibrations can be programmed at a user-specified rate either inline with sample tubes or from centralized calibration tubes (rate-driven)
- Microsoft's SQL Server 2005 Express for secure storage and fast retrieval of results
- Post-run retrospective data editing
- Wide variety of reporting and exporting options with userdefineable settings
- Optional software available to assist in achieving compliance to the US FDA's 21 CFR Part 11 requirements for audit trails, electronic signatures and access privileges

Analytical performance

Warm-up time

Warm up time from standby mode of 20 mins with < 10 mins plasma stabilization from plasma ignition

Stray light

Stray light elimination via baffles and optical design to less than 2.0 ppm effective As signal at 188.980 nm from 10 000 ppm Ca.

Signal stability

Typically stable to less than 1% RSD over 8 hours without internal standardization or any form of drift correction.

Typical resolution (FWHM)

Element	Wavelength (nm)	Resolution (pm)
As	188.980	<7
Mo	202.032	<7.2
Zn	213.857	<8
Pb	220.353	<8.2
Cr	267.716	<10
Cu	327.396	<13
Ba	614.172	<38

Analytical performance

Typical detection limits

3 sigma detection limits ($\mu g/L$) using a 30 second integration time

Element	Wavelength (nm)	725/735 radial (µg/L)	720/730 axial (µg/L)	Element	Wavelength (nm)	725/735 radial (µg/L)	720/730 axial (µg/L)
Ag	328.068	1	0.3	Mg	279.553	0.04	0.01
Al	167.019	0.9	0.1	Mn	257.610	0.08	0.03
As	188.980	5	1	Mo	202.032	1.5	0.5
Au	242.794	2.5	1	Na	589.592	2	0.15
В	249.772	0.6	0.1	Ni	231.604	1.4	0.3
Ba	455.403	0.15	0.03	Р	177.434	5	1.5
Be	313.042	0.04	0.01	Pb	220.353	5	0.8
Bi	223.061	6	2	S	181.972	9	3
Ca	396.847	0.06	0.01	Sb	206.834	5	2
Cd	214.439	0.6	0.05	Se	196.026	6	2
Се	418.659	7	2	Si	251.611	2.5	1
Co	238.892	1	0.2	Sn	189.925	7	1
Cr	267.716	0.9	0.15	Sr	407.771	0.05	0.01
Cu	327.395	1	0.3	Ti	334.941	0.25	0.1
Fe	238.204	0.8	0.1	TI	190.794	6	1.5
Hg	184.887	2	0.8	V	292.401	0.7	0.2
K	766.491	4	0.3	Zn	213.857	0.5	0.2
Li	670.783	1	0.06	Zr	343.823	0.9	0.3

Accessories

Autosampler

- Agilent SPS 3 high throughput autosampler, with fast X, Z, theta arm movement
- Capacity for up to three sample racks and two standard racks.
 Racks may be exchanged during analysis for unlimited sample capacity.
- · Fully compatible with optional online diluter
- Compatible with a wide range of commercially available, autoclavable, laboratory racks

Diluter

 Optional precision syringe auto-diluter for Agilent SPS 3, performs automatic online over-range dilution and automatic off-line sample and calibration solution preparation using optional Roboprep software

Automatic online dilution

- Online dilution of over-range elements with user-definable dilution and mixing options
- Serial dilution of samples until analyte results are in-range
- · Combine with MultiCal to further extend the linear dynamic range

Accessories

Intelligent off-line solution preparation

- Optional RoboPrep software utility allows off-line dilution and preparation of samples and standards
- Provides customization of rack configurations to allow dilution of samples directly in digestion racks
- Includes capabilities for preparation of multi-element calibration standards, sample spiking and standard addition

Productivity package

- Four port Switching Valve System (SVS 1) immediately rinses the sample introduction system while the next sample is being introduced to the instrument
- Reduces carry-over, increases sample throughput and decreases cost per analysis

Ultrasonic nebulizer

 USN increases nebulization efficiency typically providing an orderof-magnitude improvement in detection limits

Vapor generation

- Modular continuous flow vapor generator for the determination of Hg, As, Se, Sb, Te, Bi, and Sn at µg/L and ng/L levels
- · Compatible with the Agilent SPS 3 autosampler

AGM 1

 Controls addition of oxygen to the plasma to prevent carbon deposition and reduce background structure when analyzing organic solvents. Recommended when determining organic solvents using the axially-viewed ICP-0ES

Volatile organics kit

- Includes a water-cooled spraychamber and demountable torch with 0.8 mm ID injector for the analysis of volatile organics such as gasoline and naptha
- Requires, but does not include a suitable water cooler. The AGM 1 for controlled addition of oxygen to the auxiliary gas is also recommended.

Torches, nebulizers and spare parts

Agilent offers a range of torches, nebulizers, spraychambers, tubings and other spare parts. Refer to our Web site for details

Installation requirements	System installation			
		For details of ICP-OES installation requirements refer to the Pre-installation manual, publication number 8510233700		
Customer support policies	Warranty			
		Twelve (12) months, though this may vary according to location.		
	Hardware support period			
		Seven (7) years from date of last unit manufacture. After this time, parts and supplies will be provided if available.		
	Software support			
		Telediagnostic capability is available for some instrument models. Availability of Telediagnostic support may vary according to location. Software upgrades to fix nonconformances or safety problems will be issued free of charge. Software upgrades to add additional functionality will require an additional fee.		
	Online user group			
		All Agilent ICP-0ES users can join our free email users group, PlasmaNet, which has access to Agilent ICP-0ES users and Agilent support staff worldwide.		
Further details	More information			
		For further information please consult your Agilent office or supplier, or our Web site at www.agilent.com		

www.agilent.com/chem

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